Contribution ID: **17**

Type: **not specified**

Neutron induced SEEs

Tuesday 2 February 2021 15:30 (15 minutes)

Neutrons with energies between 0.1-10 MeV can significantly impact the Soft Error Rate (SER) in SRAMs and other microelectronics manufactured in scaled technologies, with respect to high-energy neutrons. Experimental measurements benchmarked with Monte Carlo simulations showed that neutrons with these energies can induce more than 60% of the overall upset rate in accelerator applications.

Presenter: CECCHETTO, Matteo (Universite Montpellier II (FR))

Session Classification: Research